

Search Notes



Application/Control No.

10/701,462

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

ONO, YOSHIHARU

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	700	7/19/2005	K-CC
	702		
	706		
	719		
	723		
438	725		
134	1.1		
134	1.2		
134	1.3	7/19/05	K-CC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Fast keywords search USPAT, USPTA-pub. EPO, JPO, IBM-TOB. Derwent	7/18/05	K-CC
inventor search	7/18/05	K-CC